

The silicon photomultiplier

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May 10, 2023

SPAD: Principles of operation

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plier

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Parameters

Quality
measures

error sources

Digital SiPM

Applications

Prospect

- p-n diode
- 3 regimes:
 - 1 simple e-h creation through impact ionization
 - 2 secondary ionization by e
 - 3 secondary ionization by e and h (quenching needed)
- e ionization is more sensitive
- n-on-p for red
- p-on-n for blue

electrical equivalent circuit of the SPAD

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Prospect



Breakdown voltage and multiplication gain

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Applications

Prospect

- breakdown voltage

$$\int_0^W \alpha_n e^{-\int_0^x (\alpha_n - \alpha_p) dx'} dx = 1$$

- V_{bd} is more advantageous for thin depletion regions

-

$$Gain = \frac{avalanche_charge}{q} = \frac{V_{ov}(C_q + C_d)}{q}$$

- gain gives signal well above noise for $q = e$

$$V_{bd}$$

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Applications

Prospect

- measuring the gain as a function of V_{bias} .
- find the derivative

temperature dependence of parameters

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Applications

Prospect

- V_{bd} increases with T
- gain increases with lower T
- DCR increases with T

PDE

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Prospect


$$PDE(V_{ov}, \lambda) = QE(\lambda)P_T(V_{ov}, \lambda)FF_{eff}(V_{ov}, \lambda)$$

SPTR

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Prospect


$$\sigma_{timing} = \frac{\sigma_{v_{noise}}}{dv/dt_{@threshold}}$$

error sources

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Applications

Prospect

■ DCR

- $\propto \frac{1}{T}$

- residue at cryo. temperature: trap assisted tunneling

■ after pulse:

- release of trapped charges in high field regions
- mitigation: slow recharge rate
- secondary photons
- mitigation: low life time substrate

Crosstalk

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Applications

Prospect

- photons arising from one cell triggering a signal in an other cell
- Mitigation: optical trenches
- delay cross talk
- Mitigation: reduce undepleted region thickness
- external crosstalk: emission of secondary photons producing reflection on "the window"
- Delayed vs. prompt cross talk.

Excess noise factor

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Applications

Prospect

- Expectation: $N_{phe} \pm \sqrt{N_{phe}}$

- we define

$$ENF = \frac{(\sigma_Q / \langle Q \rangle)^2}{(\sigma_{Q_N} / \langle Q_N \rangle)^2}$$

Saturation

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Applications

Prospect

- trade of between saturation and dead space

$$N_{fired} = N_{total} \left(1 - e^{-\frac{N_{photon} PDE \cdot ENF}{N_{total}}} \right)$$

digital SiPM

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Applications

Prospect

- each cell has it's own read out
- high data production
- compromise: small SiPM arrays

Applications

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Applications

Prospect

- TOF-PET
- PET-MR
- SPECT/MR
- HEP
 - Problem: High radiation environment
- LIDAR
- Scintillation detection
 - Cherenkov in scintillator

Prospect

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Applications

Prospect

- Digital will become more prevalent

Abbreviations

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Applications

Prospect

- SiPM: Silicon photomultiplier
- SSPM: solid state photomultiplier
- MPPC: multi pixel photon counter
- SPAD: single photon avalanche diode
- SPTR: single photon time resolution
- PDE: photon detector efficiency
- PMT: photo multiplier tube
- TCAD: technology computer aided design
- DCR: dark count rate
- LTE: light transfer efficiency
- PTS: photon transfer time spread

Abstract

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Digital SiPM

Applications

Prospect

- What is SiPM and what is it use for
- What are relevant qualitative parameters for best application specific performance

introduction

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Digital SiPM

Applications

Prospect

- Analog vs. Digital SiPM
- 10 – 100 μm wide
- single photon sensitivity
- ps timing resolution
- applications:
 - TOF-PET
 - LIDAR
 - dark matter
 - double β
 - HEP
 - much more

electronic read out

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Applications

Prospect

- high gain
- high power consumption
- strong and fast amplifier

Analog SiPM

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Applications

Prospect

- large array of SPADS in parallel
- Counting photons via integration over charge
- individual SPADS interact via capacitance